

REC'D PCT/PTO 14 FEB 2005

10 / 524506  
DT01 Rec'd PCT/PTC 1.4 FEB 2005 *FB*

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of )  
 )  
**Frederix & Hug** )  
 )  
Serial No. n/a (U.S. Nat. Stage of )  
PCT/IB2002/003253 ) Examiner: n/a  
 )  
Filed: herewith ) Group Art Unit: n/a  
 )  
For: **Sensor with Cantilever and** ) Att. Dkt.: 3024-111  
**Optical Resonator** )  
 )

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants submit herewith a listing of references cited in the International Search Report (\*), a copy of which is attached. Applicants also provide a listing of publications as well as copies of non-U.S. patent publications that the Office may wish to consider in examination of the subject application.

Respectfully submitted,

By

*Joyce von Natzmer*

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**February 14, 2005**  
Enclosures

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Complete if Known					
				Application Number		NA		10/524506	
				Nat. Phase Filing Date		February 14, 2005			
				First Named Inventor		FREDERIX			
				Group Art Unit		NA			
				Examiner Name		NA			
Sheet	1		2	Attorney Docket Number		3024-111			
<b>U.S. PATENT DOCUMENTS</b>									
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY				
		Number	Kind Code <sup>2</sup> (if known)						
		2002/000511*		Schaffer et al	01-03-2002				
		5,166,516*		Kajimura	11-24-1992				
		5,560,244*		Prater et al	10-01-1996				
		5,565,987		Jain et al	10-15-1996				
		5,465,611		Ruf et al	11-14-1995				
<b>FOREIGN PATENT DOCUMENTS</b>									
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T <sup>6</sup>		
		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)					
		EP	0 557 743*	A	IBM	09-01-1993			
		EP	0 398 085	A1	IBM	11-22-1990			
Examiner Signature						Date Considered			

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code.

<sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language translation is attached. AB indicates that only an English language abstract is attached.

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

*Complete if Known*

Application Number

NA

10/524506

**Nat. Phase Filing Date**

February 14, 2005

First Named Inventor

**FREDERIX**

## Group Art Unit

NA

**Examiner Name**

NA

Sheet

2

of

2

Attorney Docket Number

3024-111

## NON PATENT LITERATURE DOCUMENTS

Examiner  
Initials\*

Cite  
No.<sup>1</sup>

**Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published**

 $T^2$ 

Rugar D.; Mamin H. J.; and Guethner P., Improved fiber-optic interferometer for atomic force microscopy, *Applied Physics Letters*, Volume 55, Issue 25, pp. 2588-2590 (December 18, 1989).

Rugar, D.; Mamin, H. J.; Erlandsson, R.; Stern, J. E.; Terris, B. D., Force microscope using a fiber-optic displacement sensor, *Review of Scientific Instruments*, Volume 59, Issue 11, pp.2337-2340 (November 1988).

Examiner  
Signature

Date Considered